

**NeoSpectra Micro  
Reliability Qualification Tests**



Test	Conditions
High Temperature Storage Life (HTSL)	85°C, Device OFF, 500 h
Low Temperature Storage Life (LTSL)	-40°C, Device OFF, 500 h
Temperature Humidity Bias (TH) <i>(May not be relevant but passed)</i>	70°C, 85 %RH, Vcc max Device ON, 500 h
Low Temperature Operating Life (LTOL)	-20°C, Device ON, 500 h
High Temperature Operating Life (HTOL)	70°C, Device ON, 500 h
Temperature Cycling (TC)	-10°C to +60°C, Device OFF, 500 cycle, 3 cph
Shock	500g, +/- XYZ, Device OFF, 0.5ms Half-Sine, 5x

**Thank  
you**

